

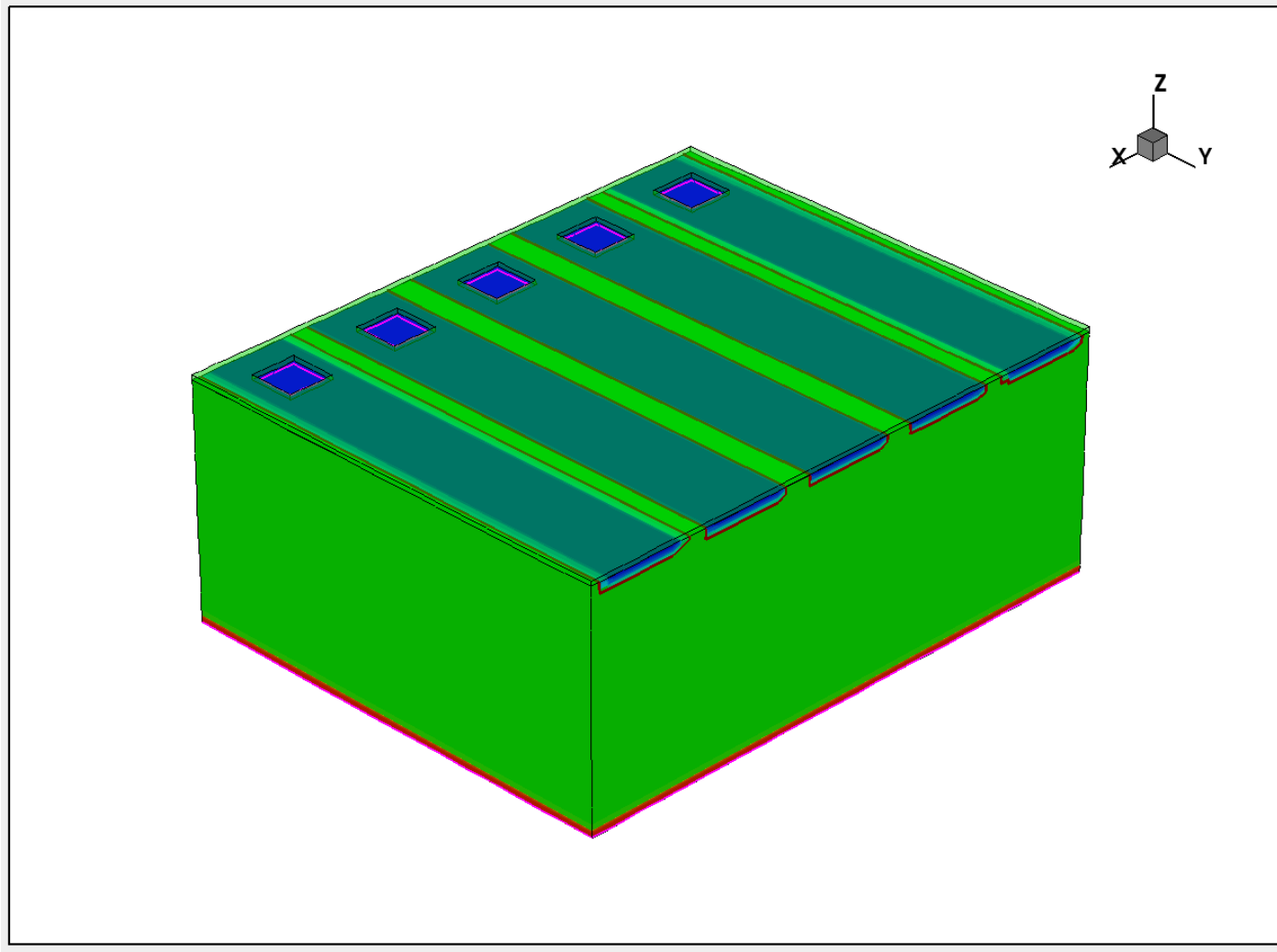
Strip detector with active edge: charge collection simulations

J. Segal, September 5 2013

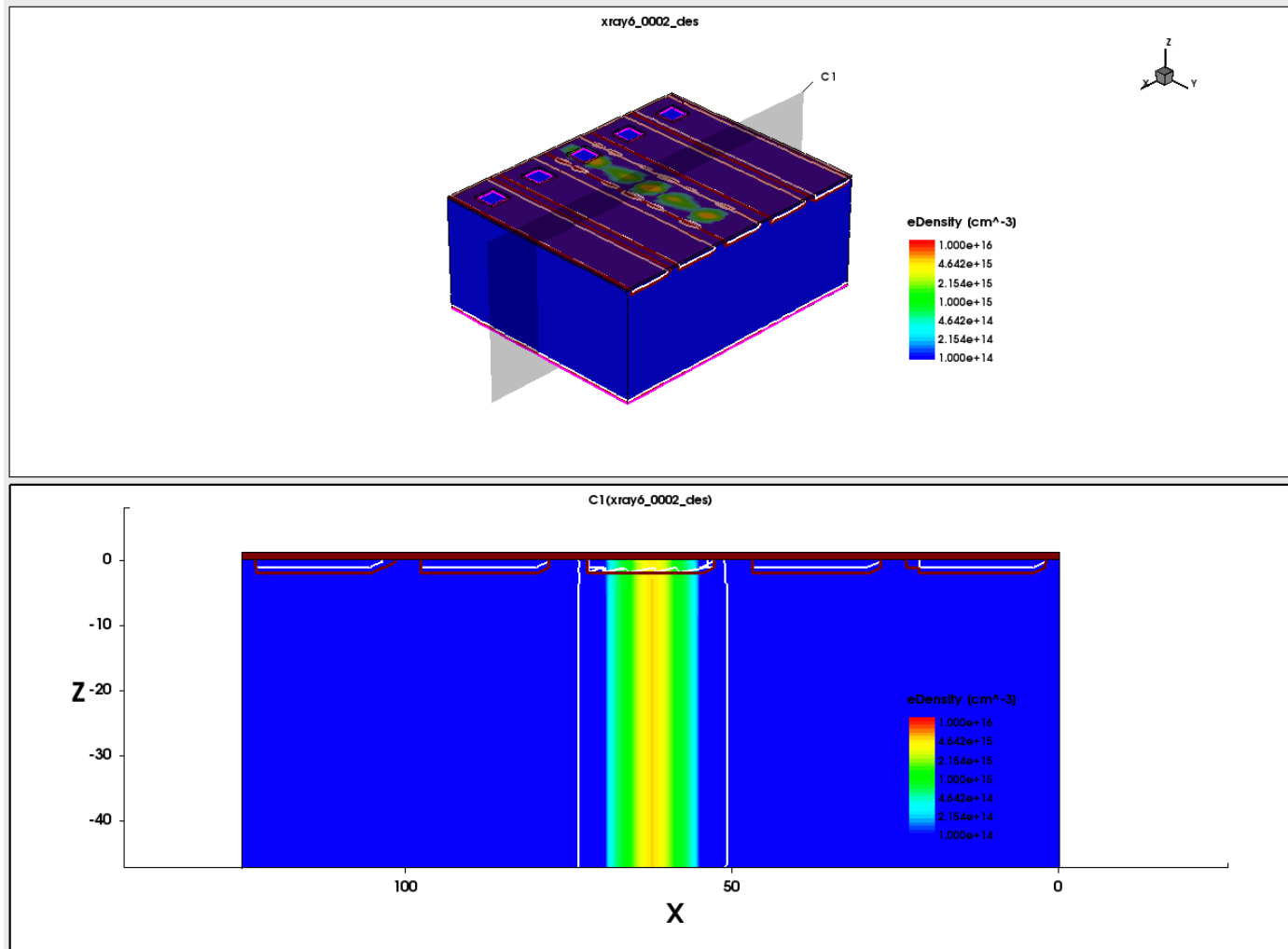
Structure: n-type substrate, n-type backside, p-type strips

Dimensions: 50 μm or 75 μm deep, 25 μm strip pitch, 100 μm strip length

Other physical parameters: 100ohms contact resistance, surface charge $5\text{e}10/\text{cm}^2$

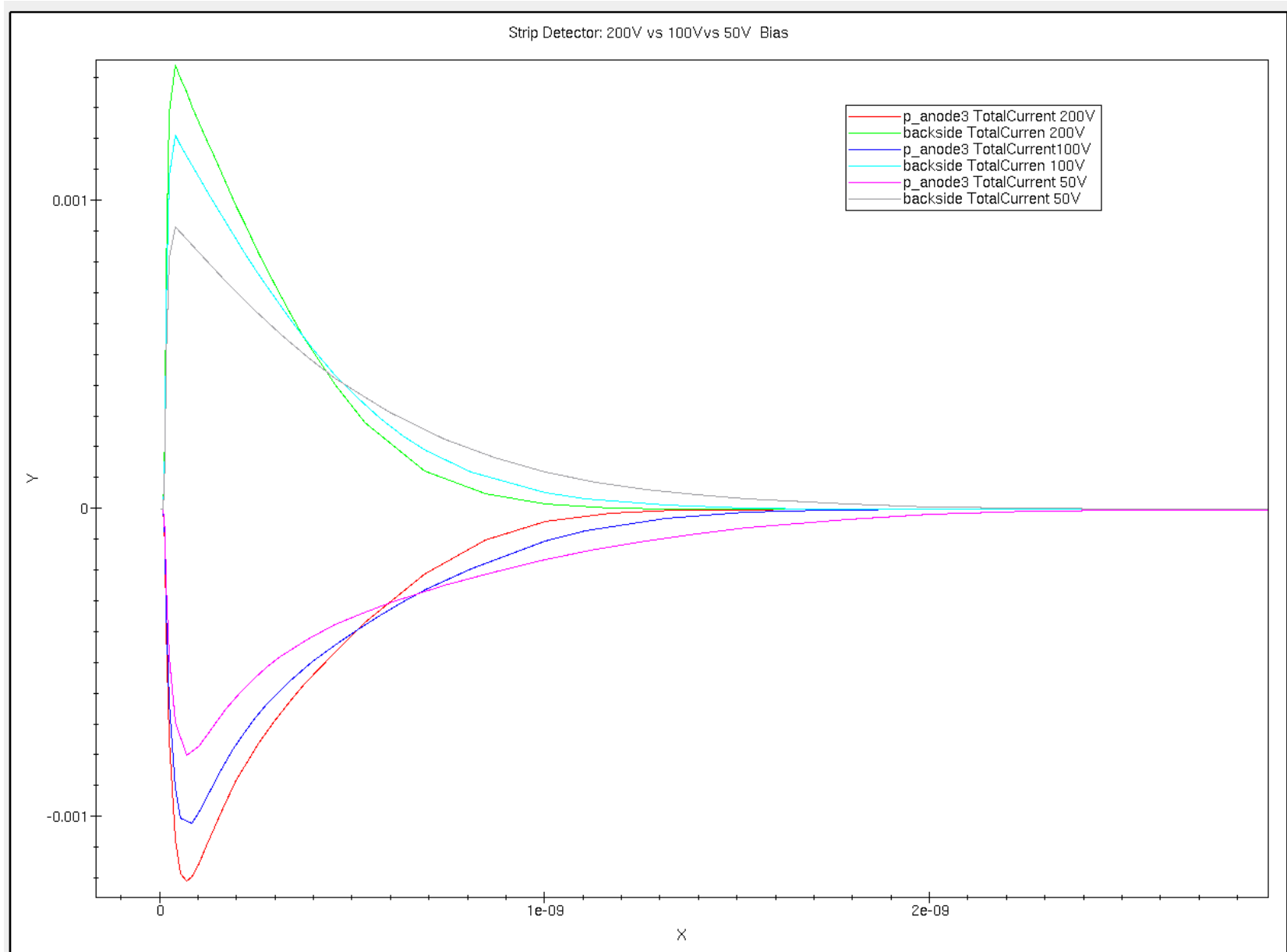


Charge Deposition in Simulation: Total 1000 10KeV photon equivalent @50um



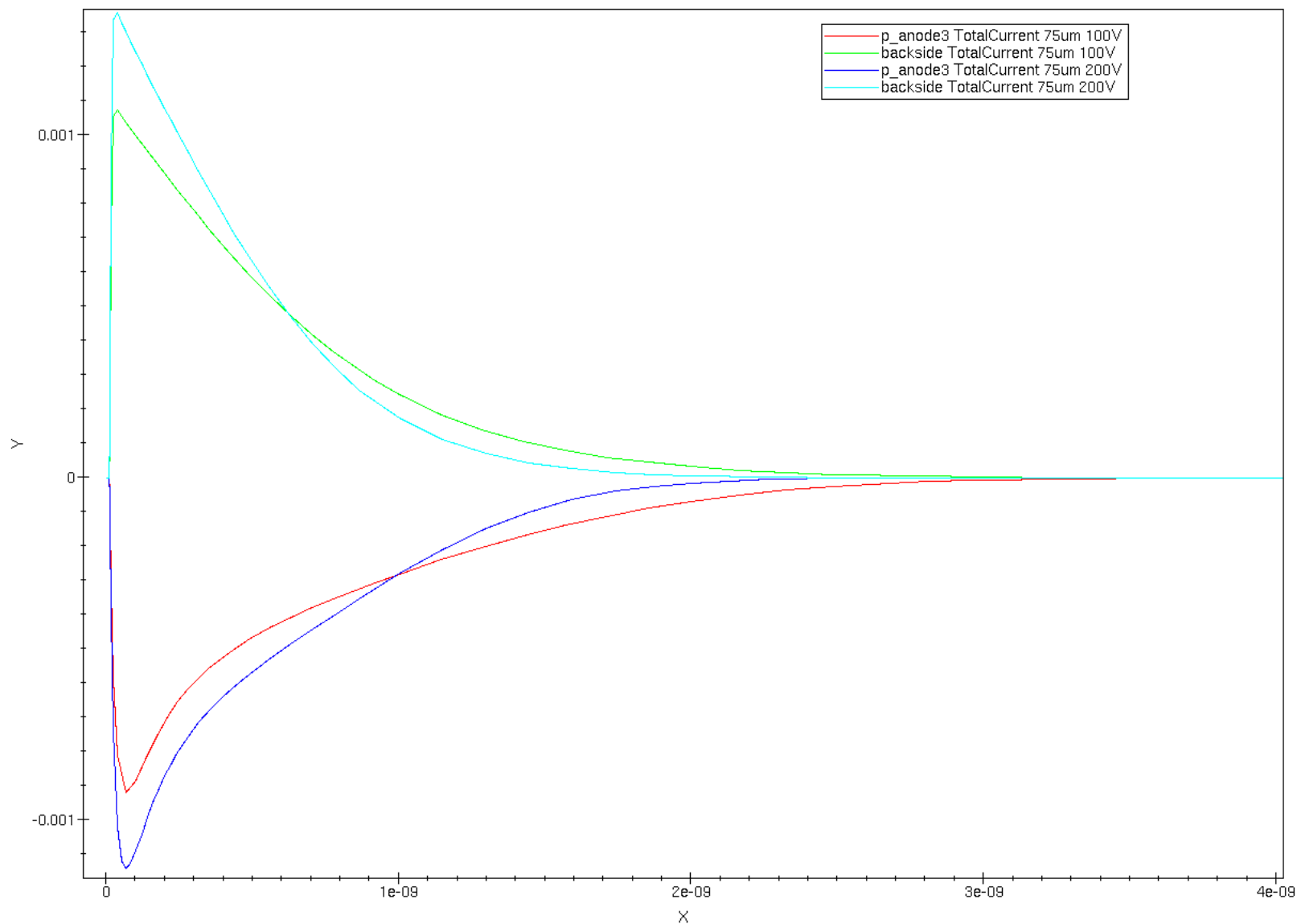
Contact Current vs. Time for 50um Thick Strip Detector

1000 10KeV Photon equivalent



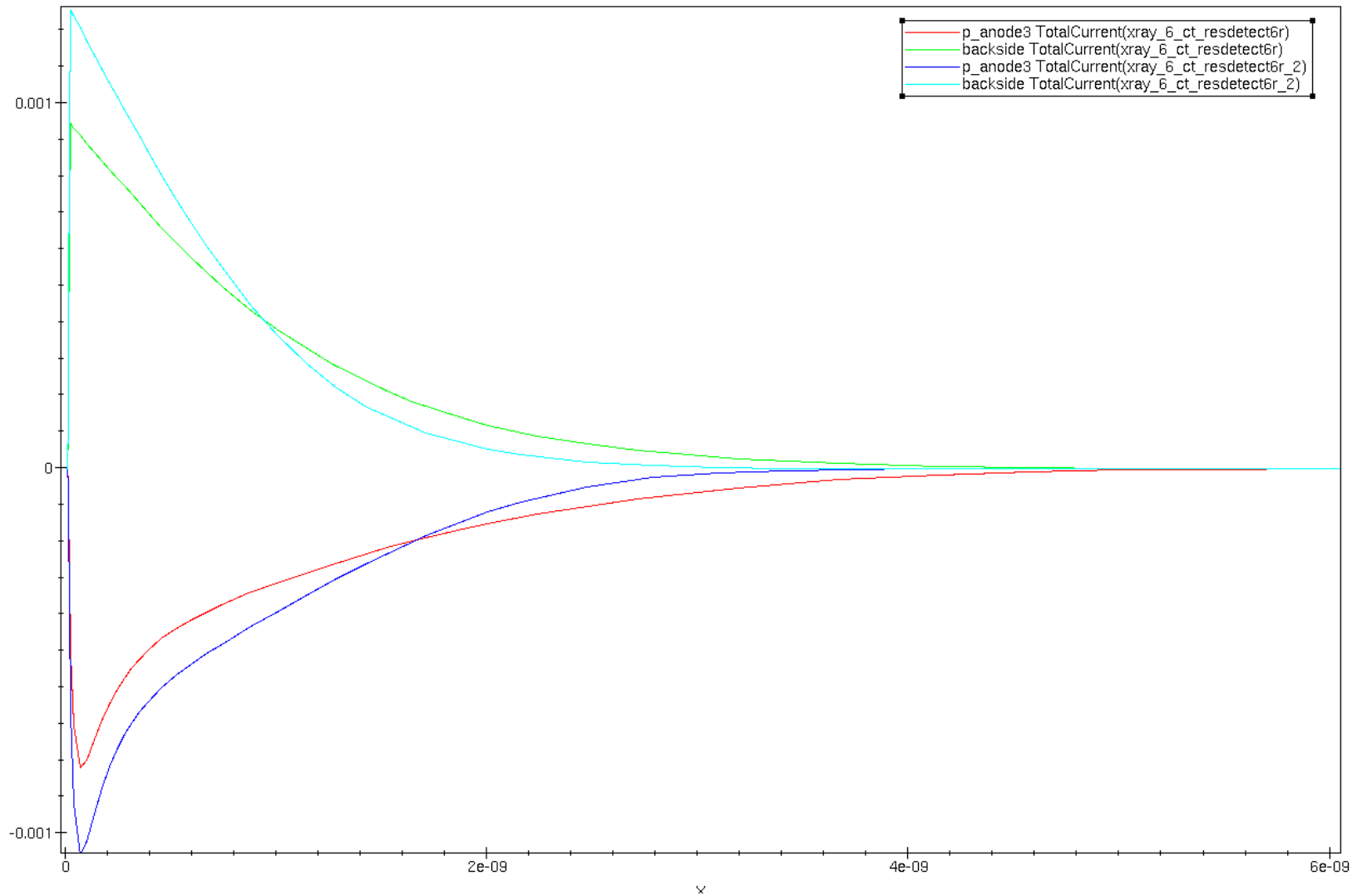
Contact Current vs. Time for 75um Thick Detector

1500 10KeV Photon Equivalent

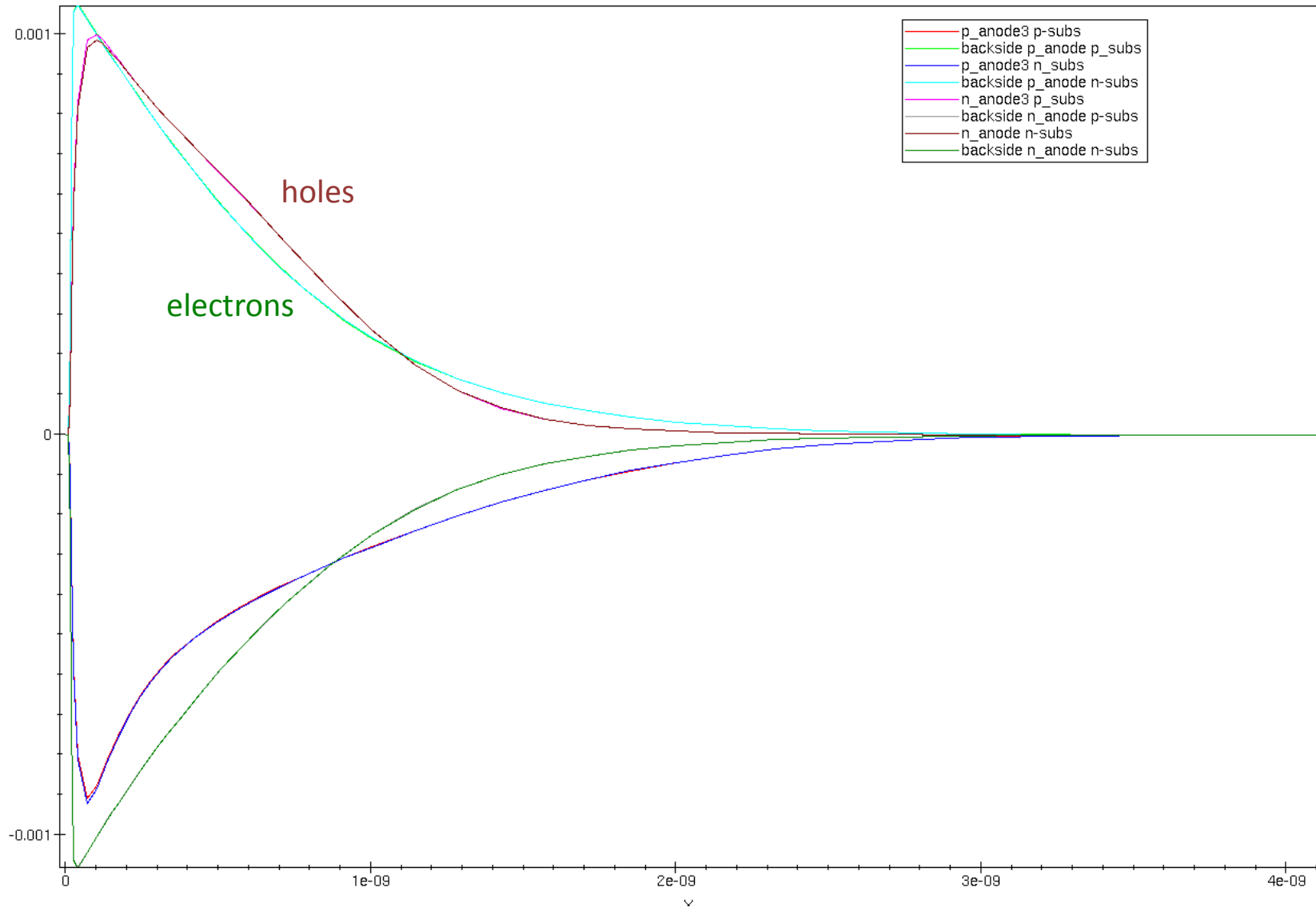


Contact Current vs. Time for 100um Thick Detector

2000 10KeV Photon Equivalent

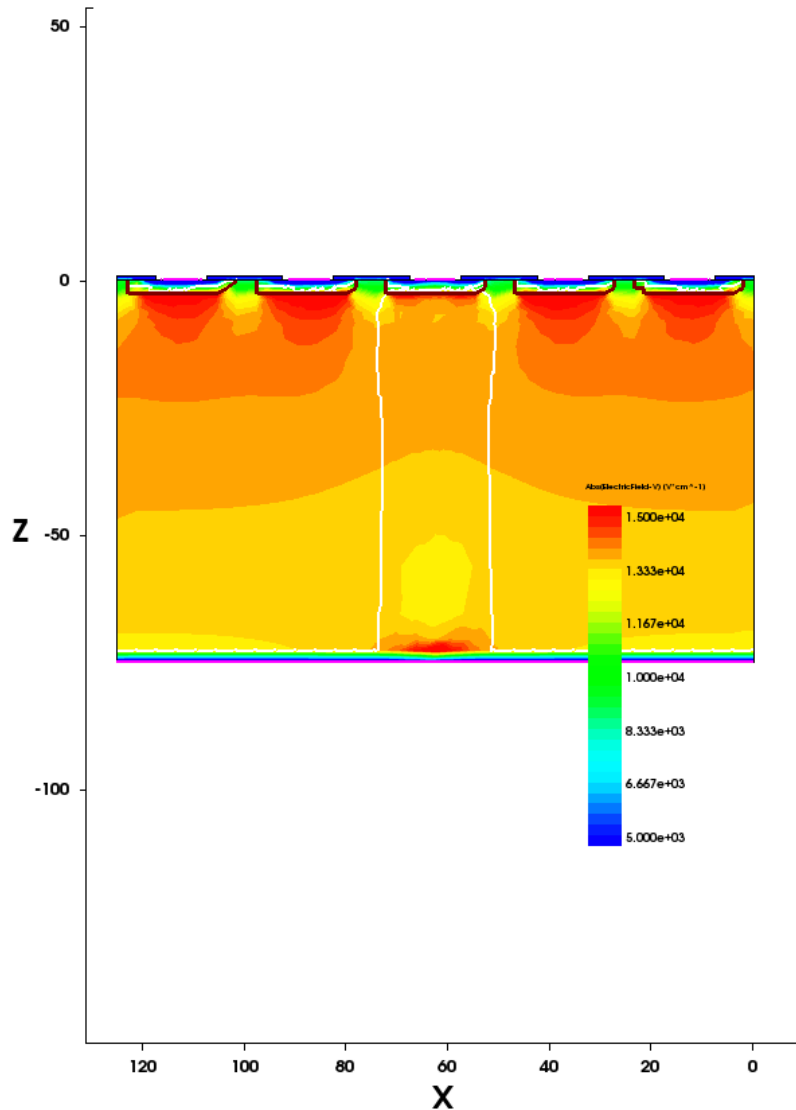


Contact Current vs. Time for 75um Thick Detector @100V for p-type vs n-type anodes (collects holes vs electrons respectively)



Electric Field Cross sections

n-type electrodes (@0.01nS)



p-type electrodes (@0.01nS)

For p-type (holes) Low field regions between electrodes due to fixed oxide charge ($5e10$ in this simulation). Surface implant would make this better or worse.

